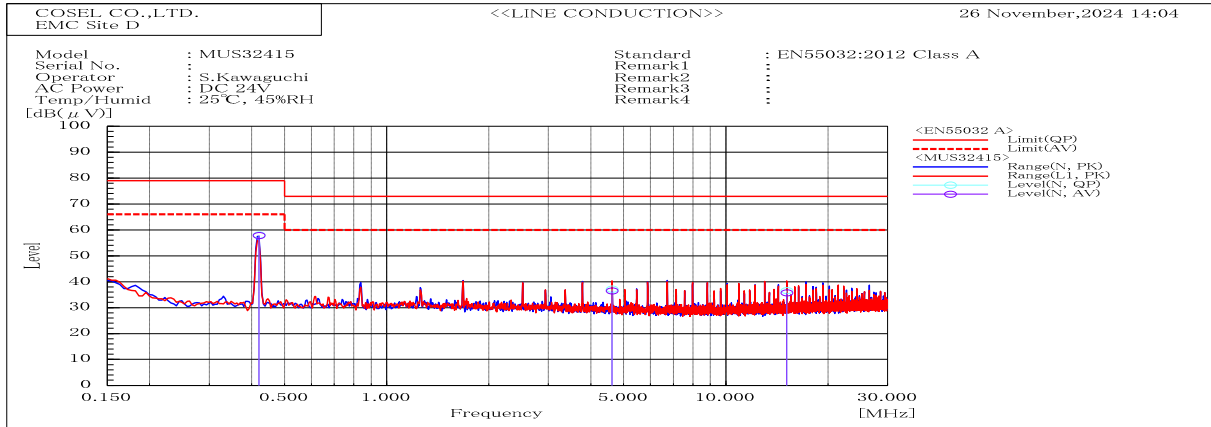
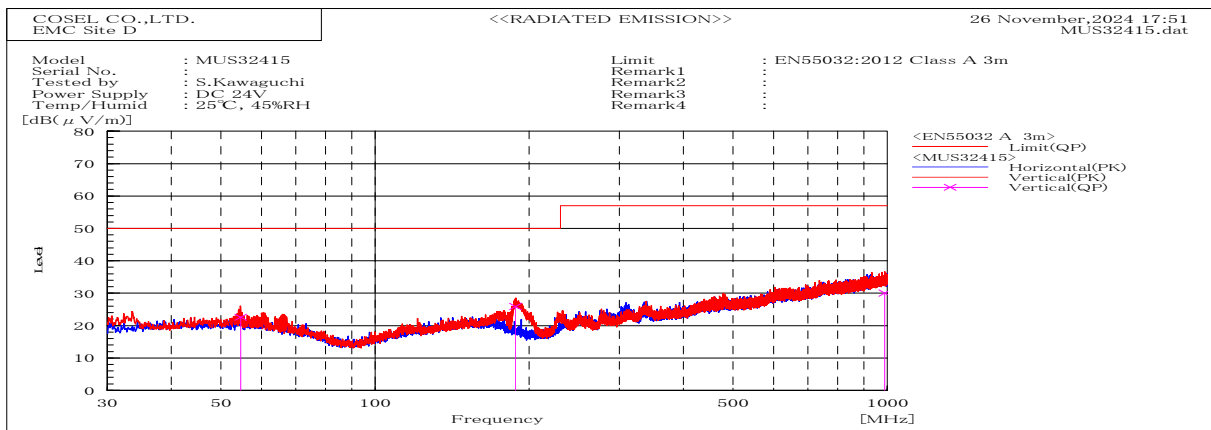


DATA SHEET		Date	26-Nov-24
Model	MUS32415	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi



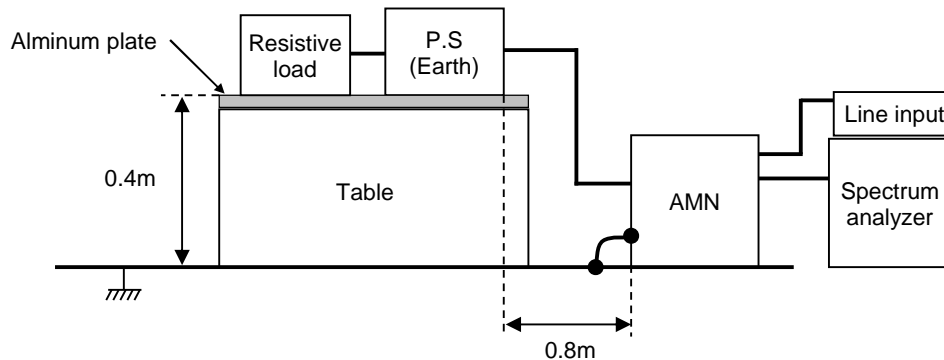
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.42	N	58	57.9	79	66	21	8.1	Pass	
4.624	N	37.1	36.5	73	60	35.9	23.5	Pass	
15.134	N	36.6	35.7	73	60	36.4	24.3	Pass	



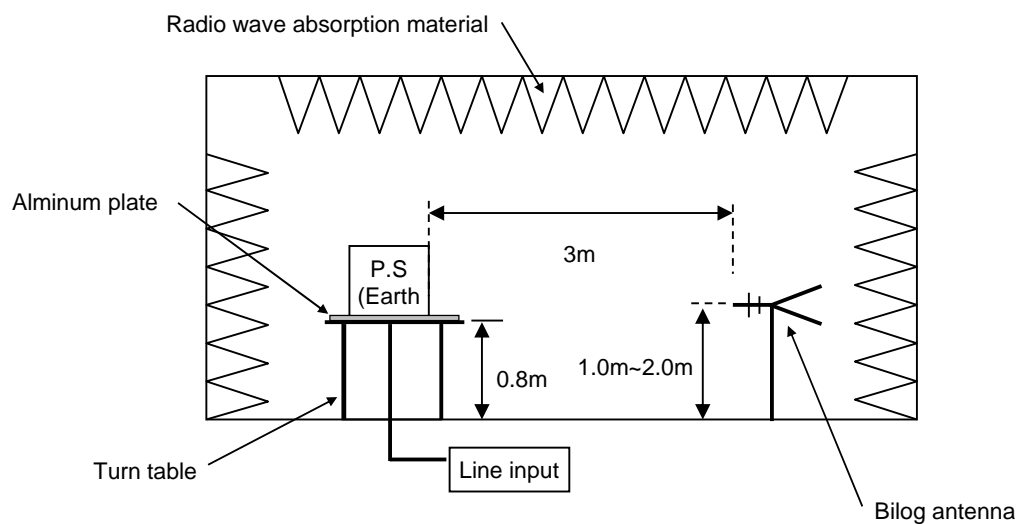
Frequency MHz	Polarization	Stability	Level dB(μV/m)		Limit dB(μV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP						
988.138	V	Stable	30	57	27	Pass	102	105.3		
54.65	V	Stable	22.6	50	27.4	Pass	100.2	0		
187.952	V	Stable	25.9	50	24.1	Pass	100.2	70.3		

DATA SHEET		Date	26-Nov-24
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi

1. Line conduction



2. Radiated emission



Conditions

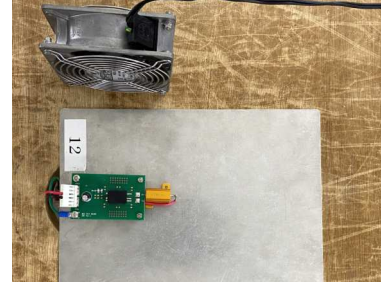
Test : EMI
Model Name: MUS3□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

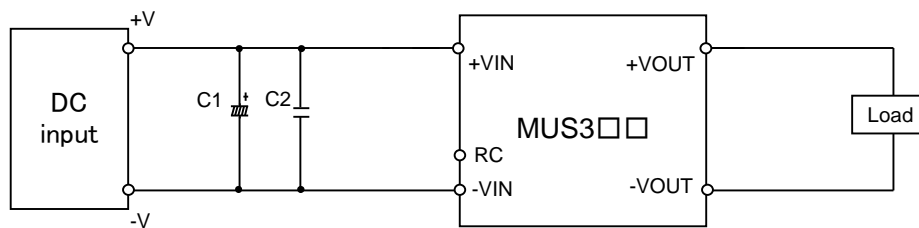


Fig.1 MUS305□, MUS312□, MUS324□ Testing circuitry

C1 :	MUS305□	16V 220 μ F	Electric capacitor (UPWseries NICHICON)
	MUS312□	50V 100 μ F	Electric capacitor (UPWseries NICHICON)
	MUS324□	-	
C2 :	MUS305□	16V 22 μ F	Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING)
	MUS312□	25V 22 μ F	Ceramic capacitor (C3216JB1E226MT TDK)
	MUS324□	50V 10 μ F	Ceramic capacitor (C3216X7R1H106KT TDK)

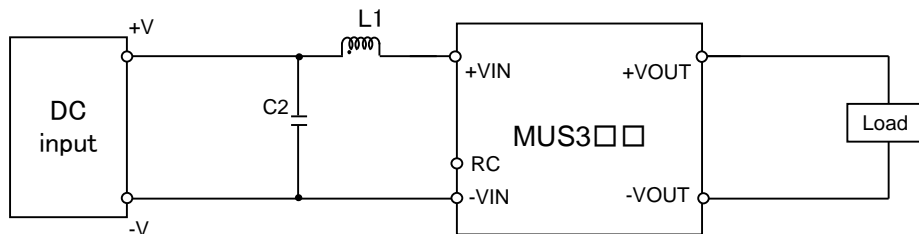


Fig.2 MUS348□ Testing circuitry

C2 :	MUS348□	100V 2.2 μ F	Ceramic capacitor (C3216X7S2A225KT TDK)
L1 :	MUS348□	520mA 15 μ H	Inductor(LQH32PN150MN0L MURATA MANUFACTURING)